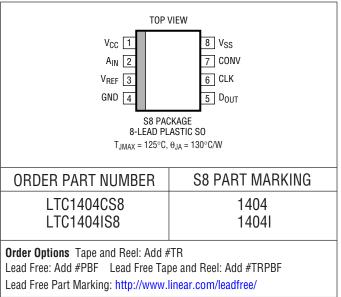
ABSOLUTE MAXIMUM RATINGS

(Notes 1, 2)
Supply Voltage (V _{CC})
Negative Supply Voltage (V _{SS}) –6V to GND
Total Supply Voltage (V _{CC} to V _{SS})
Bipolar Operation Only 12V
Analog Input Voltage (Note 3)
Unipolar Operation $-0.3V$ to (V _{CC} + 0.3V)
Bipolar Operation $(V_{SS} - 0.3V)$ to $(V_{CC} + 0.3V)$
Digital Input Voltage (Note 4)
Unipolar Operation0.3V to 12V
Bipolar Operation (V _{SS} – 0.3V) to 12V
Digital Output Voltage
Unipolar Operation $-0.3V$ to (V _{CC} + 0.3V)
Bipolar Operation $(V_{SS} - 0.3V)$ to $(V_{CC} + 0.3V)$
Power Dissipation
Operating Ambient Temperature Range
LTC1404C0°C to 70°C
LTC1404I –40°C to 85°C
Junction Temperature 125°C
Storage Temperature Range –65°C to 150°C
Lead Temperature (Soldering, 10 sec)

PACKAGE/ORDER INFORMATION



Consult LTC Marketing for parts specified with wider operating temperature ranges.

POWER REQUIREMENTS The \bullet denotes specifications which apply over the full operating temperature range, unless otherwise noted specifications are at T_A = 25°C. V_{CC} = 5V, f_{SAMPLE} = 600kHz, t_r = t_f = 5ns, unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS		MIN	TYP	MAX	UNITS
V _{CC}	Positive Supply Voltage	Unipolar		4.75		5.25	V
		Bipolar		4.75		5.25	V
V _{SS}	Negative Supply Voltage	Bipolar Only		-2.45		-5.25	V
I _{CC}	Positive Supply Current	f _{SAMPLE} = 600ksps			15	30	mA
		Nap Mode	•		1.3	3.0	mA
		Sleep Mode	•		8.0	20.0	μA
I _{SS}	Negative Supply Current	f _{SAMPLE} = 600ksps, V _{SS} = -5V			0.2	0.6	mA
		Nap Mode	•		0.2	0.5	mA
		Sleep Mode	•		4	10	μA
P _D	Power Dissipation	f _{SAMPLE} = 600ksps			75	160	mW
-		Nap Mode	•		7.5	20	mW
		Sleep Mode	•		60	150	μW

ANALOG INPUT The \bullet denotes specifications which apply over the full operating temperature range, unless otherwise noted specifications are at T_A = 25°C. V_{CC} = 5V, f_{SAMPLE} = 600kHz, t_r = t_f = 5ns, unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS		MIN TYP	MAX	UNITS
V _{IN}	Analog Input Range	$4.75V \le V_{CC} \le 5.25V$ (Unipolar) $4.75V \le V_{CC} \le 5.25V$, $-5.25V \le V_{SS} \le -2.45V$ (Bipolar)		0 to 4.096 0 to ±2.048		V V
I _{IN}	Analog Input Leakage Current	During Conversions (Hold Mode)	٠		±1	μA
C _{IN}	Analog Input Capacitance	Between Conversions (Sample Mode) During Conversions (Hold Mode)		45 5		pF pF

CONVERTER CHARACTERISTICS The \bullet denotes specifications which apply over the full operating temperature range, unless otherwise noted specifications are at T_A = 25°C. With internal reference V_{CC} = 5V, f_{SAMPLE} = 600kHz, t_r = t_f = 5ns, unless otherwise specified (Note 6).

PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
Resolution (No Missing Codes)		•	12			Bits
Integral Linearity Error	(Note 7)	•			±1	LSB
Differential Linearity Error		•			±1	LSB
Offset Error	(Note 8)	•			±6 ±8	LSB LSB
Full-Scale Error					±15	LSB
Full-Scale Tempco	$I_{OUT(REF)} = 0$	•		±10	±45	ppm/°C

DYNAMIC ACCURACY The \bullet denotes specifications which apply over the full operating temperature range, unless otherwise noted specifications are at T_A = 25°C. V_{CC} = 5V, V_{SS} = -5V, f_{SAMPLE} = 600kHz.

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
S/(N + D)	Signal-to-Noise	100kHz Input Signal 300kHz Input Signal	•	69	72 72		dB dB
THD	Total Harmonic Distortion Up to 5th Harmonic	100kHz Input Signal 300kHz Input Signal	•		-82 -80	-76	dB dB
	Peak Harmonic or Spurious Noise	100kHz Input Signal 300kHz Input Signal	•		-84 -82	-76	dB dB
IMD	Intermodulation Distortion	$f_{IN1} = 99.17$ kHz, $f_{IN2} = 102.69$ kHz $f_{IN1} = 298.68$ kHz, $f_{IN2} = 304.83$ kHz			-82 -70		dB dB
	Full Power Bandwidth				5		MHz
	Full Linear Bandwidth $(S/(N + D) \ge 68dB)$				1		MHz

INTERNAL REFERENCE CHARACTERISTICS The \bullet denotes specifications which apply over the full operating temperature range, unless otherwise noted specifications are at $T_A = 25^{\circ}C$. $V_{CC} = 5V$, $f_{SAMPLE} = 600$ kHz, $t_r = t_f = 5$ ns, unless otherwise specified.

PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
V _{REF} Output Voltage	l _{OUT} = 0		2.410	2.430	2.450	V
V _{REF} Output Tempco	$I_{OUT} = 0$	•		±10	±45	ppm/°C
V _{REF} Line Regulation	$4.75V \le V_{CC} \le 5.25V -5.25V \le V_{SS} \le 0V$			0.5 0.01		LSB/V LSB/V
V _{REF} Load Regulation	$0 \le I_{OUT} \le 1$ mA			1		LSB/mA
V _{REF} Wake-Up Time from Sleep Mode	C _{VREF} = 10µF			2.5		ms

DIGITAL INPUTS AND OUTPUTS The • denotes specifications which apply over the full operating temperature range, unless otherwise noted specifications are at $T_A = 25^{\circ}$ C. $V_{CC} = 5V$, $f_{SAMPLE} = 600$ kHz, $t_r = t_f = 5$ ns, unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
VIH	High Level Input Voltage	V _{CC} = 5.25V	•	2.0			V
V _{IL}	Low Level Input Voltage	V _{CC} = 4.75V	•			0.8	V
I _{IN}	Digital Input Current	$V_{IN} = 0V$ to V_{CC}	•			±10	μA
CIN	Digital Input Capacitance				5		pF
V _{OH}	High Level Output Voltage	$V_{CC} = 4.75V, I_0 = -10\mu A$ $V_{CC} = 4.75V, I_0 = -200\mu A$	•	4.0	4.7		V V
V _{OL}	Low Level Output Voltage	$V_{CC} = 4.75V, I_0 = 160\mu A$ $V_{CC} = 4.75V, I_0 = 1.6m A$	•		0.05 0.10	0.4	V V



DIGITAL INPUTS AND OUTPUTS range, unless otherwise noted specifications are at $T_A = 25^{\circ}C$. $V_{CC} = 5V$, $f_{SAMPLE} = 600$ kHz, $t_r = t_f = 5$ ns, unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
I _{OZ}	Hi-Z Output Leakage D _{OUT}	$V_{OUT} = 0V$ to V_{CC}	•			±10	μA
C _{OZ}	Hi-Z Output Capacitance D _{OUT}				15		pF
ISOURCE	Output Source Current	$V_{OUT} = 0V$			-10		mA
I _{SINK}	Output Sink Current	V _{OUT} = V _{CC}			10		mA

TIMING CHARACTERISTICS The \bullet denotes specifications which apply over the full operating temperature range, unless otherwise noted specifications are at T_A = 25°C. V_{CC} = 5V, f_{SAMPLE} = 600kHz, t_r = t_f = 5ns, unless otherwise specified. See Figures 12, 13, 14.

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
f _{SAMPLE(MAX)}	Maximum Sampling Frequency		•	600			kHz
t _{CONV}	Conversion Time	f _{CLK} = 9.6MHz			1.36		μs
t _{ACQ}	Acquisition Time (Unipolar Mode) (Bipolar Mode V _{SS} = -5V)				200 160		ns ns
f _{CLK}	CLK Frequency		•	0.1		9.6	MHz
t _{CLK}	CLK Pulse Width	(Notes 5 and 10)		40			ns
t _{WK(NAP)}	Time to Wake Up from Nap Mode				350		ns
t ₁	CLK Pulse Width to Return to Active Mode		•	40			ns
t ₂	CONV↑ to CLK↑ Setup Time		•	70			ns
t ₃	CONV [↑] After Leading CLK [↑]		•	0			ns
t ₄	CONV Pulse Width	(Note 9)	•	40			ns
t ₅	Time from CLK↑ to Sample Mode				60		ns
t ₆	Aperture Delay of Sample-and-Hold	Jitter < 50ps			40		ns
t ₇		(Note 5)	•		220 180	310 300	ns ns
t ₈	Delay Time, CLK↑ to D _{OUT} Valid	C _{LOAD} = 20pF			40	70	ns
tg	Delay Time, CLK↑ to D _{OUT} Hi-Z	C _{LOAD} = 20pF			40	70	ns
t ₁₀	Time from Previous Data Remains Valid After CLK↑	C _{LOAD} = 20pF	•	10	30		ns
t ₁₁	Minimum Time Between Nap/Sleep Request to Wake Up Request	(Notes 5 and 10)		50			ns

Note 1: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. Exposure to any Absolute Maximum Rating condition for extended periods may affect device reliability and lifetime.

Note 2: All voltage values are with respect to GND.

Note 3: When these pin voltages are taken below V_{SS} (ground for unipolar mode) or above V_{CC}, they will be clamped by internal diodes. This product can handle input currents greater than 60mA without latch-up if the pin is driven below V_{SS} (ground for unipolar mode) or above V_{CC} .

Note 4: When these pin voltages are taken below V_{SS} (ground for unipolar mode), they will be clamped by internal diodes. This product can handle input currents greater than 60mA without latch-up if the pin is driven below V_{SS} (ground for unipolar mode). These pins are not clamped to V_{CC} . Note 5: Guaranteed by design, not subject to test.

Note 6: Linearity, offset and full-scale specifications apply for unipolar and bipolar modes.

Note 7: Integral nonlinearity is defined as the deviation of a code from a straight line passing through the actual endpoints of the transfer curve. The deviation is measured from the center of the quantization band.

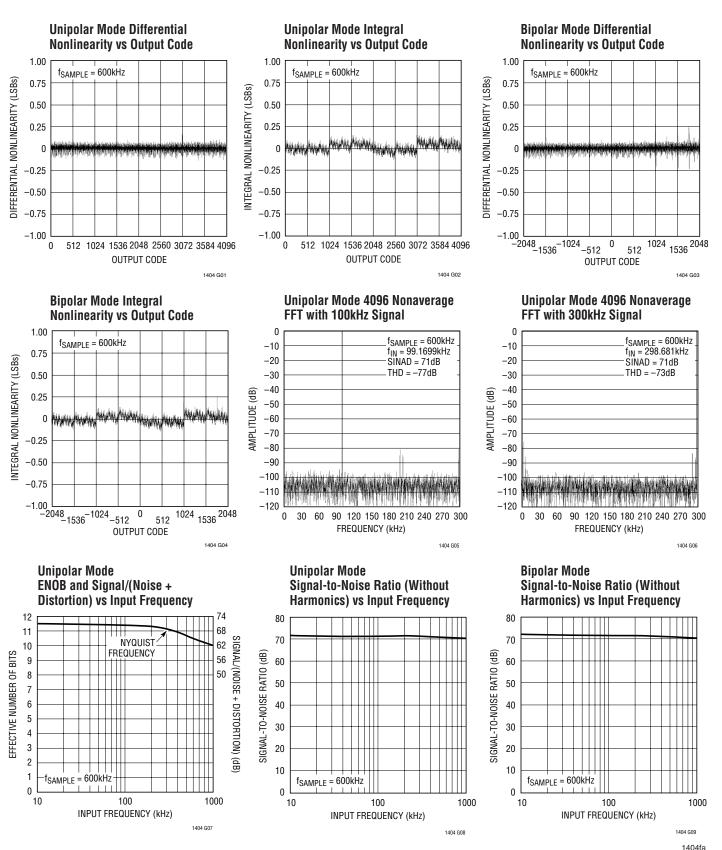
Note 8: Bipolar offset is the offset voltage measured from -0.5LSB when the output code flickers between 0000 0000 0000 and 1111 1111 1111.

Note 9: The rising edge of CONV starts a conversion. If CONV returns low at a bit decision point during the conversion, it can create small errors. For best performance, ensure that CONV returns low either within 100ns after the conversion starts (i.e., before the first bit decision) or after the 14 clock cycles. (Figure 13 Timing Diagram).

Note 10: If this timing specification is not met, the device may not respond to a request for a conversion. To recover from this condition a NAP request is required.

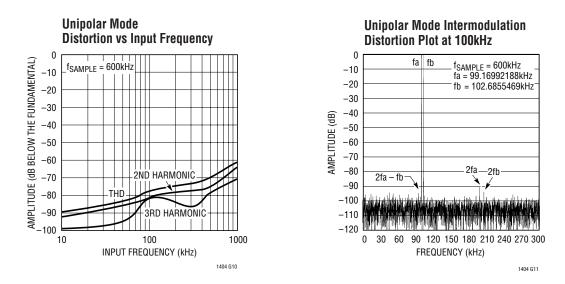




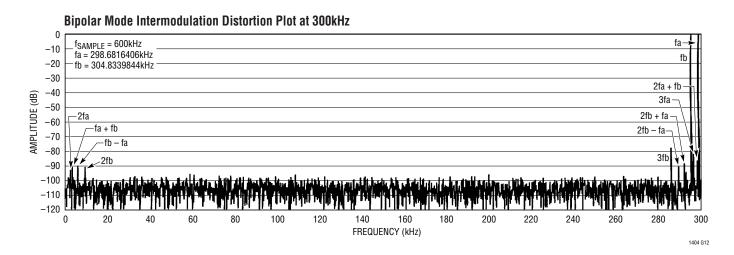




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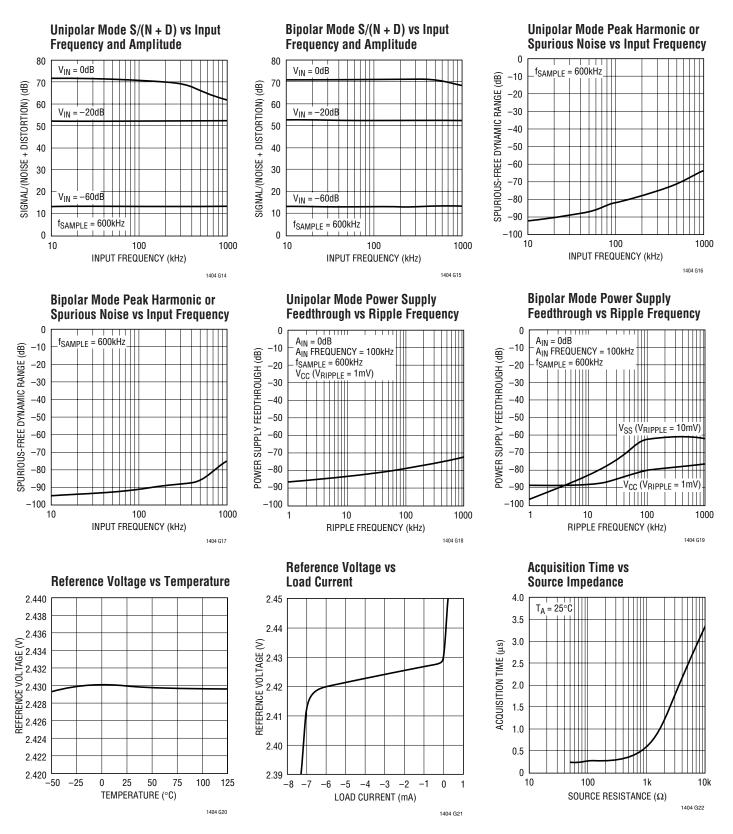


Unipolar Mode Intermodulation Distortion Plot at 300kHz 0 f_{SAMPLE} = 600kHz fa = 298.6816406kHz fa--10 fb -20 fb = 304.8339844kHz -30 -40 AMPLITUDE (dB) 2fa + fb-50 3fa -60 2fb - fa 2fa -70 fa + fb 3fb -80 2fb -90 -100-110 -120 20 40 60 80 100 120 160 180 200 220 240 260 280 0 140 300 FREQUENCY (kHz) 1404 G12



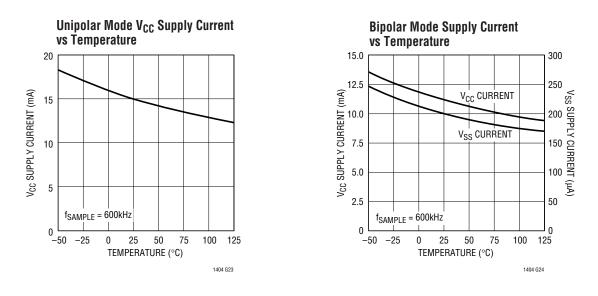
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PIN FUNCTIONS

 V_{CC} (Pin 1): Positive Supply, 5V. Bypass to GND (10µF tantalum in parallel with 0.1µF ceramic).

A_{IN} (Pin 2): Analog Input. 0V to 4.096V (Unipolar), ±2.048V (Bipolar).

 V_{REF} (Pin 3): 2.43V Reference Output. Bypass to GND (10µF tantalum in parallel with 0.1µF ceramic).

GND (Pin 4): Ground. GND should be tied directly to an analog ground plane.

D_{OUT} (**Pin 5**): The A/D conversion result is shifted out from this pin.

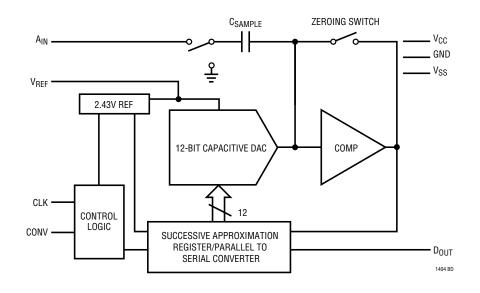
CLK (Pin 6): Clock. This clock synchronizes the serial data transfer. A minimum CLK pulse of 40ns signals the ADC to wake up from Nap or Sleep mode.

CONV (Pin 7): Conversion Start Signal. This active high signal starts a conversion on its rising edge. Keeping CLK low and pulsing CONV two/four times will put the ADC into Nap/Sleep mode.

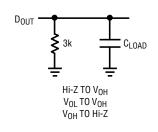
 V_{SS} (Pin 8): Negative Supply. -5V for bipolar operation. Bypass to GND with $10\mu F$ tantalum in parallel with $0.1\mu F$ ceramic. V_{SS} should be tied to GND for unipolar operation.

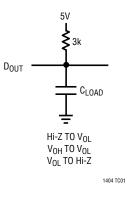


FUNCTIONAL BLOCK DIAGRAM



TEST CIRCUITS





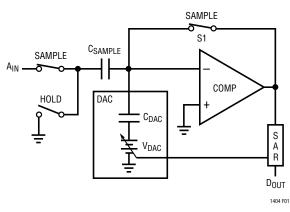


Conversion Details

The LTC1404 uses a successive approximation algorithm and an internal sample-and-hold circuit to convert an analog signal to a 12-bit serial output based on a precision internal reference. The control logic provides easy interface to microprocessors and DSPs through 3-wire connections.

A rising edge on the CONV input starts a conversion. At the start of a conversion the successive approximation register (SAR) is reset. Once a conversion cycle has begun, it cannot be restarted.

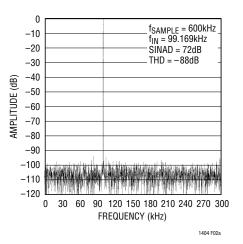
During conversion, the internal 12-bit capacitive DAC output is sequenced by the SAR from the most significant bit (MSB) to the least significant bit (LSB). Referring to Figure 1, the A_{IN} input connects to the sample-and-hold capacitor during the acquired phase and the comparator offset is nulled by the feedback switch. In this acquire phase, it typically takes 160ns for the sample-and-hold capacitor to acquire the analog signal. During the convert phase, the comparator feedback switch opens, putting the comparator into the compare mode. The input switches connect C_{SAMPLF} to ground, injecting the analog input charge onto the summing junction. This input charge is successively compared with the binary-weighted charges supplied by the capacitive DAC. Bit decisions are made by the high speed comparator. At the end of a conversion, the DAC output balances the A_{IN} input charge. The SAR contents (a 12-bit data word) which represent the input voltage, are presented through the serial pin D_{OUT} .





Dynamic Performance

The LTC1404 has excellent high speed sampling capability. FFT (Fast Fourier Transform) test techniques are used to test the ADC's frequency response, distortion and noise at the rated throughput. By applying a low distortion sine wave and analyzing the digital output using an FFT algorithm, the ADC's spectral content can be examined for frequencies outside the fundamental. Figure 2a shows a typical LTC1404 FFT plot.





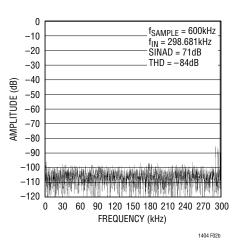


Figure 2b. LTC1404 Nonaveraged, 4096 Point FFT Plot with 300kHz Input Frequency in Bipolar Mode





Signal-to-Noise Ratio

The signal-to-noise plus distortion ratio [S/(N + D)] is the ratio between the RMS amplitude of the fundamental input frequency to the RMS amplitude of all other frequency components at the A/D output. The output is band limited to frequencies from DC to half the sampling frequency. Figure 2a shows a typical spectral content with a 600kHz sampling rate and a 100kHz input. The dynamic performance is excellent for input frequencies up to the Nyquist limit of 300kHz as shown in Figure 2b.

Effective Number of Bits

The effective number of bits (ENOBs) is a measurement of the effective resolution of an ADC and is directly related to the S/(N + D) by the equation:

$$N = \frac{S/(N+D) - 1.76}{6.02}$$

where N is the effective number of bits of resolution and S/(N + D) is expressed in dB. At the maximum sampling rate of 600kHz, the LTC1404 maintains very good ENOBs up to the Nyquist input frequency of 300kHz (refer to Figure 3).

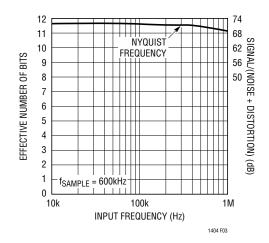


Figure 3. Effective Bits and Signal-to-Noise + Distortion vs Input Frequency in Bipolar Mode

Total Harmonic Distortion

Total harmonic distortion (THD) is the ratio of the RMS sum of all harmonics of the input signal to the fundamental itself. The out-of-band harmonics alias into the frequency band between DC and half of the sampling frequency. THD is expressed as:

$$THD = 20 log \frac{\sqrt{V2^2 + V3^2 + V4^2 + \dots Vn^2}}{V1}$$

where V1 is the RMS amplitude of the fundamental frequency and V2 through Vn are the amplitudes of the second through nth harmonics. THD vs input frequency is shown in Figure 4. The LTC1404 has good distortion performance up to the Nyquist frequency and beyond.

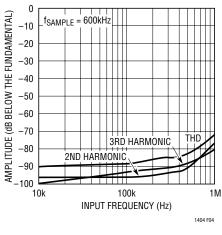


Figure 4. Distortion vs Input Frequency in Bipolar Mode

Intermodulation Distortion

If the ADC input signal consists of more than one spectral component, the ADC transfer function nonlinearity can produce intermodulation distortion (IMD) in addition to THD. IMD is the change in one sinusoidal input caused by the presence of another sinusoidal input at a different frequency.



If two pure sine waves of frequencies fa and fb are applied to the ADC input, nonlinearities in the ADC transfer function can create distortion products at sum and difference frequencies of mfa \pm nfb, where m and n = 0, 1, 2, 3, etc. For example, the 2nd order IMD terms include (fa + fb) and (fa - fb) while the 3rd order IMD terms includes (2fa + fb), (2fa - fb), (fa + 2fb) and (fa - 2fb). If the two input sine waves are equal in magnitude, the value (in decibels) of the 2nd order IMD products can be expressed by the following formula.

 $IMD(fa \pm fb) = 20log \frac{Amplitude at (fa \pm fb)}{Amplitude at fa}$

Figure 5 shows the IMD performance at a 100kHz input.

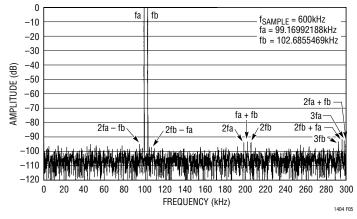


Figure 5. Intermodulation Distortion Plot in Bipolar Mode

Peak Harmonic or Spurious Noise

The peak harmonic or spurious noise is the largest spectral component excluding the input signal and DC. This value is expressed in decibels relative to the RMS value of a full-scale input signal.

Full Power and Full Linear Bandwidth

The full power bandwidth is the input frequency at which the amplitude of the reconstructed fundamental is reduced by 3dB for a full-scale input signal.

The full linear bandwidth is the input frequency at which the S/(N + D) has dropped to 68dB (11 effective bits). The

LTC1404 has been designed to optimize input bandwidth, allowing the ADC to undersample input signals with frequencies above the converter's Nyquist Frequency. The noise floor stays very low at high frequencies; S/(N + D) becomes dominated by distortion at frequencies far beyond Nyquist.

Driving the Analog Input

The analog input of the LTC1404 is easy to drive. It draws only one small current spike while charging the sampleand-hold capacitor at the end of a conversion. During conversion, the analog input draws only a small leakage current. The only requirement is that the amplifier driving the analog input must settle after the small current spike before the next conversion starts. Any op amp that settles in 160ns to small load current transient will allow maximum speed operation. If a slower op amp is used, more settling time can be provided by increasing the time between conversions. Suitable devices capable of driving the ADC's A_{IN} input include the LT[®]1360 and the LT1363 op amps.

The LTC1404 comes with a built-in unipolar/bipolar detection circuit. If the V_{SS} potential is forced below GND, the internal circuitry will automatically switch to bipolar mode.

The following list is a summary of the op amps that are suitable for driving the LTC1404, more detailed information is available in the Linear Technology databooks or the Linear Technology Web site.

LT 1215/LT1216: Dual and quad 23MHz, 50V/ μ s single supply op amps. Single 5V to \pm 15V supplies, 6.6mA specifications, 90ns settling to 0.5LSB.

LT1223: 100MHz video current feedback amplifier. \pm 5V to \pm 15V supplies, 6mA supply current. Low distortion up to and above 600kHz. Low noise. Good for AC applications.

LT1227: 140MHz video current feedback amplifier. \pm 5V to \pm 15V supplies, 10mA supply current. Lowest distortion at frequencies above 600kHz. Low noise. Best for AC applications.



LT1229/LT1230: Dual and quad 100MHz current feedback amplifiers. $\pm 2V$ to $\pm 15V$ supplies, 6mA supply current each amplifier. Low noise. Good AC specs.

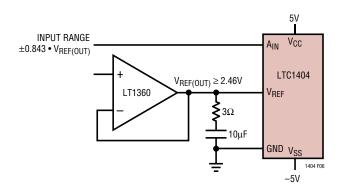
LT1360: 37MHz voltage feedback amplifier. \pm 5V to \pm 15V supplies. 3.8mA supply current. Good AC and DC specs. 70ns settling to 0.5LSB.

LT1363: 50MHz, 450V/ μ s op amps. \pm 5V to \pm 15V supplies. 6.3mA supply current. Good AC and DC specs. 60ns settling to 0.5LSB.

LT1364/LT1365: Dual and quad 50MHz, 450V/ μ s op amps. \pm 5V to \pm 15V supplies, 6.3mA supply current per amplifier. 60ns settling to 0.5LSB.

Internal Reference

The LTC1404 has an on-chip, temperature compensated, curvature corrected, bandgap reference, which is factory trimmed to 2.43V. It is internally connected to the DAC and is available at Pin 3 to provide up to 1mA of current to an external load. For minimum code transition noise, the reference output should be decoupled with a capacitor to filter wideband noise from the reference (10 μ F tantalum in parallel with a 0.1 μ F ceramic). The V_{REF} pin can be driven with a DAC or other means to provide input span adjustment in bipolar mode. The V_{REF} pin must be driven to at least 2.46V to prevent conflict with the internal reference. The reference should not be driven to more than 5V. Figure 6 shows an LT 1360 op amp driving the reference pin. Figure 7 shows a typical reference, the LT1019A-5 connected to the LTC1404. This will provide an improved





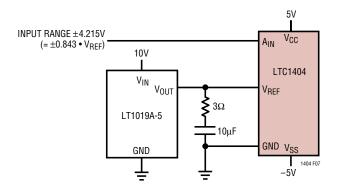


Figure 7. Supplying a 5V Reference Voltage to the LTC1404 with the LT1019A-5

drift (equal to the maximum 5ppm/°C of the LT1019A-5) and a \pm 4.215V full scale. If V_{REF} is forced lower than 2.43V, the REFRDY bit in the serial data output will be forced to low.

UNIPOLAR / BIPOLAR OPERATION AND ADJUSTMENT

Figure 8 shows the ideal input/output characteristics for the LTC1404. The code transitions occur midway between successive integer LSB values (i.e., 0.5LSB, 1.5LSB, 2.5LSB, ... FS – 1.5LSB). The output code is straight binary with 1LSB = 4.096V/4096 = 1mV. Figure 9 shows the input/output transfer characteristics for the bipolar mode in two's complement format.

Unipolar Offset and Full-Scale Error Adjustments

In applications where absolute accuracy is important, offset and full-scale errors can be adjusted to zero. Figure 10a shows the extra components required for full-scale error adjustment. Figure 10b shows offset and full-scale adjustment. Offset error must be adjusted before full-scale error. Zero offset is achieved by applying 0.5mV (i.e., 0.5LSB) at the input and adjusting the offset trim until the LTC1404 output code flickers between 0000 0000 0000 and 0000 0001. For zero full-scale error, apply an analog input of 4.0945V (FS – 1.5LSB or last code transition) at the input and adjust R5 until the LTC1404 output code flickers between 1111 1111 1111 1111

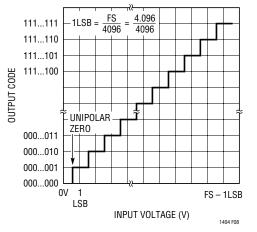


Figure 8. LTC1404 Unipolar Transfer Characteristics

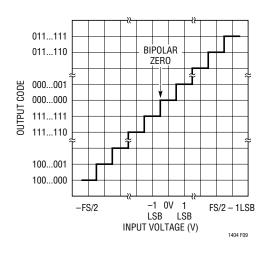


Figure 9. LTC1404 Bipolar Transfer Characteristics

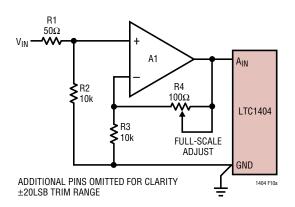


Figure 10a. LTC1404 Full-Scale Adjust Circuit

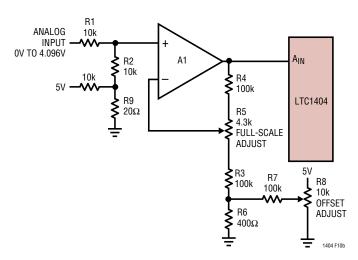
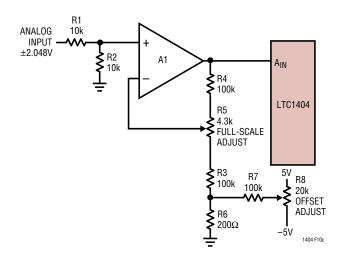


Figure 10b. LTC1404 Offset and Full-Scale Adjust Circuit





Bipolar Offset and Full-Scale Error Adjustments

Bipolar offset and full-scale errors are adjusted in a similar fashion to the unipolar case. Bipolar offset error adjustment is achieved by applying an input voltage of -0.5mV (-0.5LSB) to the input in Figure 10c and adjusting the op amp until the ADC output code flickers between 0000 0000 0000 and 1111 1111 1111. For full-scale adjustment, an input voltage of 2.0465V (FS – 1.5LSBs) is applied to the input and R5 is adjusted until the output code flickers between 0111 1111 1110 and 0111 1111 1111.



BOARD LAYOUT AND BYPASSING

To obtain the best performance from the LTC1404, a printed circuit board is required. Layout for the printed circuit board should ensure that digital and analog signal lines are separated as much as possible. In particular, care should be taken not to run any digital traces alongside an analog signal trace or underneath the ADC. The analog input should be screened by GND.

High quality 10µF surface mount AVX capacitor with a 0.1μ F ceramic should be used at the V_{CC}, V_{SS} and V_{REF} pins. For better results, another 10µFAVX capacitor can be added to the V_{CC} pin. At 600ksps, the CLK frequency can be as high as 9.6MHz. A poor quality capacitor can lose more than 80% of its capacitance at this frequency range. Therefore, it is important to consult the manufacturer's data sheet before the capacitor is used. For the LTC1404, at 600ksps, every bit decision must be determined within 104ns (9.6MHz). During this short time interval, the supply disturbance due to a CLK transition needs to settle. The ADC must update its DAC, make a comparator decision based on sub-mV overdrive, latch the new DAC information and output the serial data. This ADC provides one power supply, V_{CC} , which is connected to both the internal analog and digital circuitry. Any ringing due to poor supply or reference bypassing, inductive trace runs, CLK and CONV over- or undershoot, or unnecessary Dout loading can cause ADC errors. Therefore, the bypass capacitors must be located as close to the pins as possible. The traces connecting the pins and the bypass capacitors must be kept short and should be made as wide as possible. In unipolar mode operation, V_{SS} must be connected to the GND pin directly.

Input signal leads to A_{IN} and signal return leads from GND (Pin 4) should be kept as short as possible to minimize noise coupling. In applications where this is not possible, a shielded cable between the analog input signal and the ADC is recommended. Also, any potential difference in grounds between the analog signal and the ADC appears as an error voltage in series with the analog input signal. Attention should be paid to reducing the ground circuit impedance as much as possible.

Figure 11 shows the recommended system ground connections. All analog circuitry grounds should be terminated at the LTC1404 GND pin. The ground return from the LTC1404 Pin 4 to the power supply should be low impedance for noise free operation. Digital circuitry grounds must be connected to the digital supply common. As an alternative, instead of a direct short between the digital and analog circuitry, a 10Ω or a ferrite bead jumper helps reduce the digital noise.

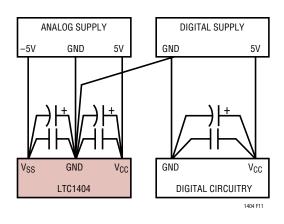


Figure 11. Power Supply Connection

In applications where the ADC data outputs and control signals are connected to a continuously active microprocessor bus, it is possible to get errors in the conversion results. These errors are due to feedthrough from the microprocessor to the successive approximation comparator. The problem can be eliminated by forcing the microprocessor into a Wait state during conversion or by using three-state buffers to isolate the ADC data bus.

Power-Down Mode

Upon power-up, the LTC1404 is initialized to the active state and is ready for conversion. However, the chip can be easily placed into Nap or Sleep mode by exercising the right combination of CLK and CONV signals. In Nap mode, all power is off except for the internal reference, which is still active and provides 2.43V output voltage to the other circuitry. In this mode, the ADC draws only 7.5mW of power instead of 75mW (for minimum power, the logic

inputs must be within 500mV of the supply rails). In Sleep mode, power consumption is reduced to 60μ W by cutting off power to all internal circuitry including the reference. Figure 12 illustrates power-down modes for the LTC1404. The chip enters Nap mode by keeping the CLK signal low and pulsing the CONV signal twice. For Sleep mode operation, the CONV signal should be pulsed four times while CLK is kept low. Nap and Sleep modes are activated on the falling edge of the CONV pulse.

The LTC1404 returns to active mode easily. The rising edge of CLK wakes up the LTC1404. From Nap mode, wake-up occurs within 350ns. During the transition from Sleep mode to active mode, the V_{REF} voltage ramp-up time is a function of its loading conditions. With a 10µF bypass capacitor, the wake-up time from Sleep mode is typically 2.5ms. A REFRDY signal is activated once the reference has settled and is ready for an A/D conversion. This REFRDY bit is sent to the D_{OUT} pin as the first bit followed by the 12-bit data word (refer to Figure 13). To save power during wake-up from Sleep mode, the chip is designed to enter Nap mode automatically until the reference is ready. Once REFRDY goes high, the comparator powers up immediately and is ready for a conversion. During the Nap interval, any attempt to perform an analog-to-digital con-

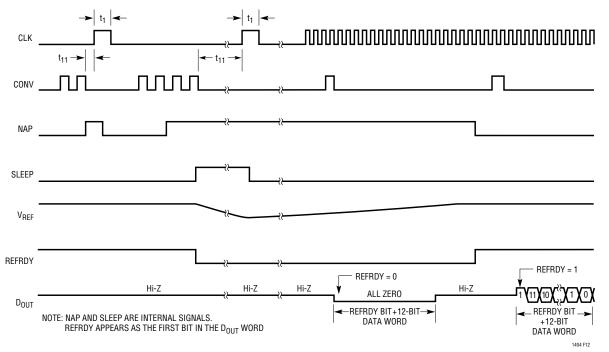
version will result in an all-zero output code, including the REFRDY bit. If no conversion is attempted, the D_{OUT} pin remains in a high impedance state. If the ADC wakes from Sleep mode, this can be determined by monitoring the state of the REFRDY bit at the D_{OUT} pin.

DIGITAL INTERFACE

The digital interface requires only three digital lines. CLK and CONV are both inputs, and the D_{OUT} output provides the conversion result in serial form.

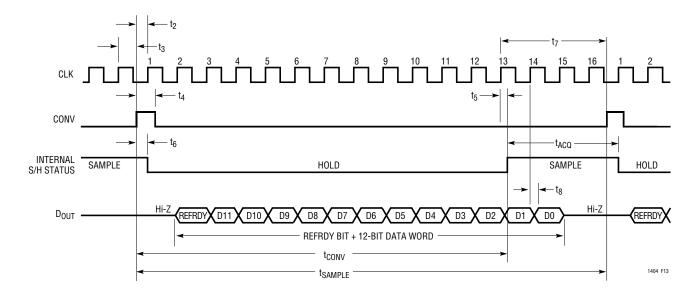
Figure 13 shows the digital timing diagram of the LTC1404 during the A/D conversion. The CONV rising edge starts the conversion. Once initiated, it can not be restarted until the conversion is completed. If the time from CONV signal to CLK rising edge is less than t_2 , the digital output will be delayed by one clock cycle.

The digital output data is updated on the rising edge of the CLK line. The digital output data consists of a REFRDY bit followed by a valid 12-bit data word. D_{OUT} data should be captured by the receiving system on the rising CLK edge. Data remains valid for a minimum time of t_{10} after the rising CLK edge to allow capture to occur.











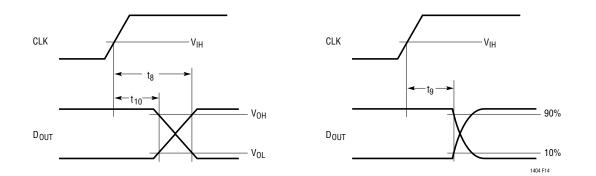
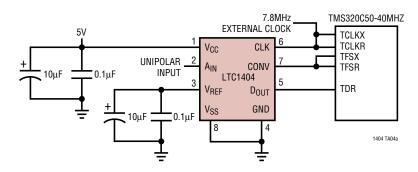


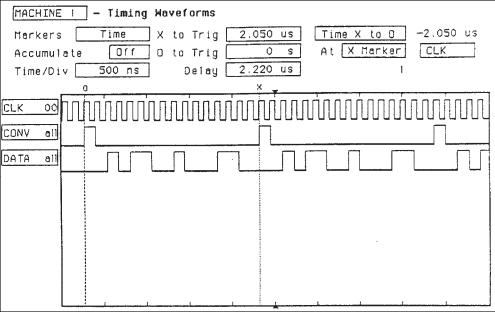
Figure 14. CLK to D_{OUT} Delay



Hardware Interface to the TMS320C50's TDM Serial Port (Frame Sync is Generated from TFSX)



Logic Analyzer Waveforms Show 2.05µs Throughput Rate (Input Voltage = 1.606V, Output Code = 0110 0100 0110 = 160610)

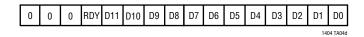


NOTE: THE TMS320C50-40MHz HAS A LIMITED SERIAL PORT CLOCK SPEED OF 7.8MHz. TO ALLOW THE LTC1404 TO RUN AT ITS MAXIMUM SPEED OF 9.6MHz, THE TMS320C50-57 OR TMS320C50-80MHz IS NEEDED

Data from the LTC1404 Loaded into the TMS320C50's TRCV Register

Х	RDY	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	DO	Х	Х
														14	04 TA040

Data Stored in the TMS320C50's Memory (in Right Justified Format)

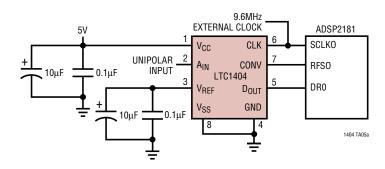




TMS320C50 Code for Circuit

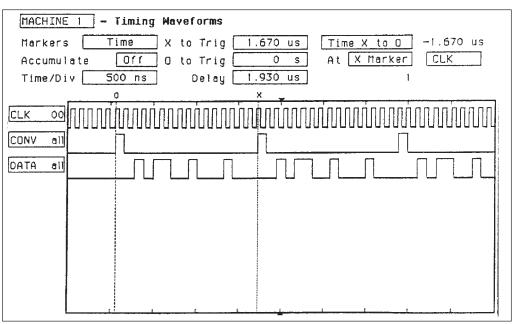
THIS PROGRAM DEMONSTRATES THE LTC1404 INTERFACE TO THE TMS320C50. FRAME SYNC PULSE IS GENERATED FROM TFSX. DATA SHIFT CLOCK IS EXTERNALLY GENERATED.	*Start Serial Communication* SACL TDXR ; Generate frame sync pulse SPLK #040h, IMR ; Turn on TRNT receiver interrupt
Initialization .mmregs ; Defines global symbolic names	CLRC INTM ; Enable interrupt CLRC SXM ; For Unipolar input, set for right shift
; Initialized data memory to zero .ds 0F00h ; Initialize data to zero DATAO .word 0 ; Begin sample data location	MAR *, AR7 LAR AR7, #0F00h ; toad the auxiliary register pointer with seven ; Load the auxiliary register seven with #0F00h ; as the begin address for data storage
DATA1 .word 0 ; . DATA2 .word 0 ; Location of data DATA3 .word 0 ; .	WAIT: NOP ; Wait for a receive interrupt NOP ; NOP ;
DATA4 .word 0 ; . DATA5 .word 0 ; End sample data location ; Set up the ISR vector	SACL TDXR ; !! Regenerate the frame sync pulse B WAIT ;
.ps 080Ah ; Serial ports interrupts rint : B RECEIVE : 0A;	; end of main program ; *Receiver Interrupt Service Routine*
xint : B TRANSMIT ; 0C; trnt : B TREC ; 0E; txnt : B TTRANX ; 10; ; Setup the reset vector .ps 0A00h .entry START:	TREC: LAMM TRCV ; Load the data received from LTC1404 SFR ; Shift right two times SFR ; AND #1FFFh, 0 ; ANDed with #1FFFh ; For converting the data to right ; justified format
TMS320C50 Initialization SETC INTM ; Temporarily disable all interrupts LDP #0 ; Set data page pointer to zero OPL #0834h, PMST ; Set up the PMST status and control register LACC #0 SAMM CWSR ; Set software wait state to 0 SAMM PDWSR ;	SACL *+, 0 LACC AR7 SUB #0F05h,0 BCND END_TRCV, GEQ Write to data memory pointed by AR7 and increase the memory address by one Compare to end sample address #0F05h if the end sample address has exceeded jump to END_TRCV
*Configure Serial Port SPLK #0028h, TSPC ; Set TDM Serial Port	SPLK #040h, IMR ; Else Re-enable the TRNT receive interrupt ; Retern to main program and enable interrupt
; TDM = 0 Stand Alone mode ; DLB=0 Not loop back ; F0=0 16 Bits ; FSM=1 Burst Mode ; MCM=0 CLKR is generated externally ; TXM=1 FSX as output pin ; Put serial port into reset	*After Obtained the Data from LTC1404, Program Jump to END_TRCV* END_TRCV: SPLK #002h, IMR ; Enable INT2 for program to halt CLRC INTM SUCCESS: B SUCCESS
; (XRST=RRST=0) SPLK #00E8h, TSPC ; Take Serial Port out of reset ; (XRST=RRST=1)	*Fill the Unused Interrupt with RETE, to avoid program get "lost"* TTRANX: RETE
SPLK #0FFFFh, IFR ; Clear all the pending interrupts	RECEIVE: RETE TRANSMIT: RETE
	INT2: B halt; Halts the running CPU

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LTC1404 Interface to the ADSP2181's SPORTO (Frame Sync is Generated from RFS0)





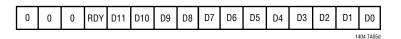
NOTE: WITHOUT THE EXTERNAL CLOCKING SIGNAL, THE ADSP2181 SCLK0 CAN BE PROGRAMMED TO RUN AT 8.3MHz

1404 TA05b

Data from the LTC1404 (Normal Mode)

X RDY D11 D10 D9 D8 D7 D6 D5 D4 D3 D2 D1 D0 X X

Data Stored in the ADSP2181's Memory (Normal Mode, SLEN = D)



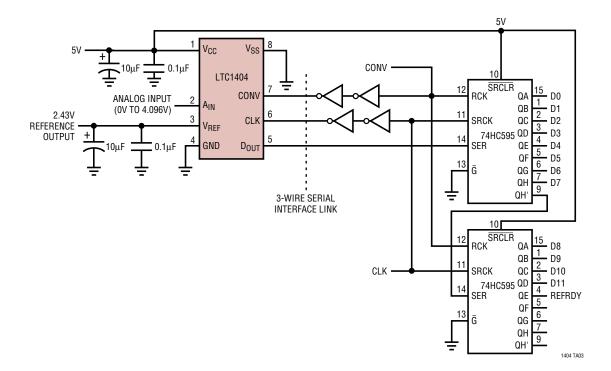




ADSP2181 Code for Circuit

THE ADSP-2181. FRA DATA SHIFT /* Section 1: Initialization .module/ram/abs = 0 ads jump start; nop; nop; nop; rti; rti; rti; rti; rti; rti; rti; rti; rti; rti; rti; rti; rti; rti; rti; rti; ax0 = rx0; dm (0x2000) = ax0; rti; rti; rti; rti; rti; rti; rti; rti; rti;	<pre>####################################</pre>	/*Section 3: configure /*Using an external clo /*Does not need to cor /*to Configure RFSDIV ax0 = 15; dm(0x3FF4) =ax0; /*to setup interrupt*/ ifc= 0x0066; icntl= 0; imask= 0x0020;	nfigure CLKDIV*/
rti; rti; rti; /*Section 2: Configure S start: /*to configure SPORTO of ax0 = 0x2F0D;	/*code vectors here upon POWER DOWN int*/ PORT0*/	/*to configure system ax0 = dm(0x3FFF); ay0 = 0xFFF0; ar = ax0 AND ay0; ay0 = 0x1000; ar = ar OR ay0; dm(0x3FFF) = ar;	



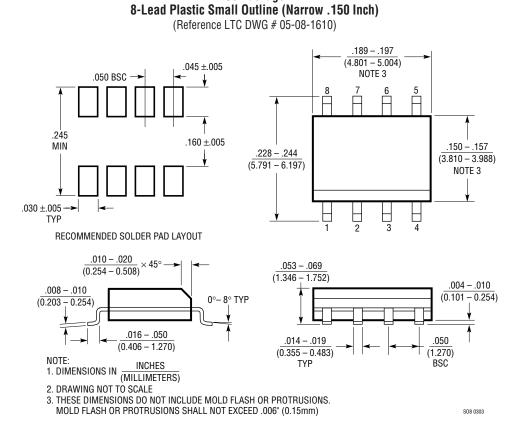


Quick Look Circuit for Converting Data to Parallel Format



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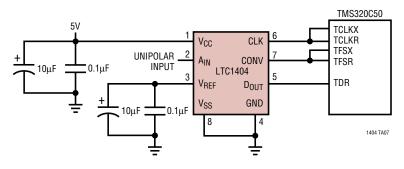
PACKAGE DESCRIPTION



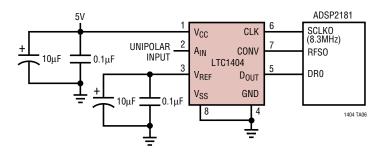
S8 Package



LTC1404 Interface to TMS320C50 Running at 5MHz without External Clock



LTC1404 Interface to ADSP2181 Running at 8.3MHz without External Clock



RELATED PARTS

PART NUMBER	DESCRIPTION	COMMENTS	
LTC1285/LTC1288	12-Bit, 3V, 7.5/6.6ksps, Micropower Serial ADCs	0.48mW, 1-/2-Channel Input, SO-8	
LTC1286/LTC1298	12-Bit, 5V, 12.5/11.16ksps, Micropower Serial ADCs	1.25mW, 1-/2-Channel Input, SO-8	
LTC1290	12-Bit, 50ksps 8-Channel Serial ADC	5V or ±5V Input Range, 30mW, Full-Duplex	
LTC1296	12-Bit, 46.5ksps 8-Channel Serial ADC	5V or ±5V Input Range, 30mW, Half-Duplex	
LTC1403/LTC1403A	12-/14-Bit 2.8Msps Serial ADCs	3V, 15mW, MSOP-10 Package, Unipolar Input	
LTC1403-1/LTC1403A-1	12-/14-Bit, 2.8Msps Serial ADCs	3V, 15mW, MSOP-10 Package, Bipolar Input	
LTC1407/LTC1407A	12-/14-Bit, 3Msps Simultaneous Sampling ADCs	3V, 14mW, 2-Channel Unipolar Differential Inputs, MSOP-10	
LTC1407-1/LTC1407A-1	12-/14-Bit, 3Msps Simultaneous Sampling ADCs	3V, 14mW, 2-Channel Bipolar Differential Inputs, MSOP-10	
LTC1417	14-Bit, 400ksps Serial ADC	5V or ±5V, 20mW, Internal Reference, SSOP-16	
LTC1609	16-Bit, 200ksps Serial ADC	5V, Configurable Bipolar or Unipolar Inputs to $\pm 10V$	
LTC1860L/LTC1861L	12-Bit, 3V, 150ksps Serial ADCs	1.22mW, 1-/2-Channel Input, MSOP-8 and SO-8	
LTC1860/LTC1861	12-Bit, 5V, 250ksps Serial ADCs	4.25mW, 1-/2-Channel Input, MSOP-8 and SO-8	
LTC1864L/LTC1865L	16-Bit, 3V, 150ksps Serial ADCs	1.22mW, 1-/2-Channel Input, MSOP-8 and SO-8	
LTC1864/LTC1865	16-Bit, 5V, 250ksps Serial ADCs	4.25mW, 1-/2-Channel Input, MSOP-8 and SO-8	